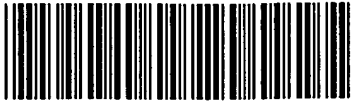


Search Notes

Application/Control No.

10/647,540

Examiner

Alex Liew

Applicant(s)/Patent under
Reexamination

NAPHADE ET AL.

Art Unit

2624

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 382 | 227 | 1/17/2007 | AL |
| 382 | 180 | 1/19/2007 | AL |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--------------------------------|-----------|------|
| 382/224 limited to text search | 1/17/2007 | AL |
| 382/181 limited to text search | 1/28/2007 | AL |
| 382/173 limited to text search | 1/19/2007 | AL |
| 382/117 limited to text search | 1/25/2007 | AL |
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